

PCTWORLD INTELLECTUAL PROPERTY ORGANIZATION
International Bureau

INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(51) International Patent Classification : Not classified	A2	(11) International Publication Number: WO 00/41518 (43) International Publication Date: 20 July 2000 (20.07.00)
(21) International Application Number: PCT/US00/00155 (22) International Filing Date: 5 January 2000 (05.01.00) (30) Priority Data: 09/227,957 11 January 1999 (11.01.99) US 09/263,653 5 March 1999 (05.03.99) US (71) Applicant: APPLIED MATERIALS, INC. [US/US]; 3050 Bowers Avenue, Santa Clara, CA 95054 (US). (72) Inventors: LANDAU, Uziel; 13909 Larchmere Boulevard, Cleveland, OH 44120 (US). D'URSO, John, J.; 2307 South Glenwood Avenue, Niles, OH 44446 (US). (74) Agents: PATTERSON, B., Todd et al.; Thomason, Moser & Patterson, L.L.P., Suite 1500, 3040 Post Oak Boulevard, Houston, TX 77056 (US).		(81) Designated States: CN, JP, KR, European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE). Published <i>Without international search report and to be republished upon receipt of that report.</i>
(54) Title: ELECTRODEPOSITION CHEMISTRY FOR FILLING OF APERTURES WITH REFLECTIVE METAL (57) Abstract The present invention provides plating solutions, particularly copper plating solutions, designed to provide uniform coatings on substrates and to provide substantially defect free filling of small features formed on substrates with none or low supporting electrolyte, <i>i.e.</i> , which include no acid, low acid, no base, or no conducting salts, and/or high metal ion, <i>e.g.</i> , copper, concentration. Defect free filling of features is enhanced by a plating solution containing blends of polythethers ("carrier") and organic divalent sulfur compounds ("accelerator"), wherein the concentration of the carrier ranges from about 0.1 ppm to about 2500 ppm of the plating solution, and the concentration of the accelerator ranges from about 0.05 ppm to about 1000 ppm of the plating solution. The plating solution is further improved by adding an organic nitrogen compound at a concentration from about 0.01 ppm to about 1000 ppm to improve the filling of vias on a resistive substrate. The organic nitrogen is preferably a substituted thiadiazole, which is used at concentrations from 0.1 ppm to about 50 ppm of the plating solution, or a quaternary nitrogen compound, which is used at concentrations from about 0.01 ppm to about 500 ppm.		

FOR THE PURPOSES OF INFORMATION ONLY

Codes used to identify States party to the PCT on the front pages of pamphlets publishing international applications under the PCT.

AL	Albania	ES	Spain	LS	Lesotho	SI	Slovenia
AM	Armenia	FI	Finland	LT	Lithuania	SK	Slovakia
AT	Austria	FR	France	LU	Luxembourg	SN	Senegal
AU	Australia	GA	Gabon	LV	Latvia	SZ	Swaziland
AZ	Azerbaijan	GB	United Kingdom	MC	Monaco	TD	Chad
BA	Bosnia and Herzegovina	GE	Georgia	MD	Republic of Moldova	TG	Togo
BB	Barbados	GH	Ghana	MG	Madagascar	TJ	Tajikistan
BE	Belgium	GN	Guinea	MK	The former Yugoslav Republic of Macedonia	TM	Turkmenistan
BF	Burkina Faso	GR	Greece			TR	Turkey
BG	Bulgaria	HU	Hungary	ML	Mali	TT	Trinidad and Tobago
BJ	Benin	IE	Ireland	MN	Mongolia	UA	Ukraine
BR	Brazil	IL	Israel	MR	Mauritania	UG	Uganda
BY	Belarus	IS	Iceland	MW	Malawi	US	United States of America
CA	Canada	IT	Italy	MX	Mexico	UZ	Uzbekistan
CF	Central African Republic	JP	Japan	NE	Niger	VN	Viet Nam
CG	Congo	KE	Kenya	NL	Netherlands	YU	Yugoslavia
CH	Switzerland	KG	Kyrgyzstan	NO	Norway	ZW	Zimbabwe
CI	Côte d'Ivoire	KP	Democratic People's Republic of Korea	NZ	New Zealand		
CM	Cameroon	KR	Republic of Korea	PL	Poland		
CN	China	KZ	Kazakhstan	PT	Portugal		
CU	Cuba	LC	Saint Lucia	RO	Romania		
CZ	Czech Republic	LI	Liechtenstein	RU	Russian Federation		
DE	Germany	LK	Sri Lanka	SD	Sudan		
DK	Denmark	LR	Liberia	SE	Sweden		
EE	Estonia			SG	Singapore		

ELECTRODEPOSITION CHEMISTRY FOR FILLING OF APERTURES WITH REFLECTIVE METAL

BACKGROUND OF THE INVENTION

Field of the Invention

The present invention relates to new formulations of metal plating solutions designed to provide uniform coatings on substrates and to provide defect free filling of small features, *e.g.*, micron scale features and smaller, formed on substrates with metals.

Background of the Related Art

Electrodeposition of metals has recently been identified as a promising deposition technique in the manufacture of integrated circuits and flat panel displays. As a result, much effort is being focused in this area to design hardware and chemistry to achieve high quality films on substrates which are uniform across the area of the substrate and which can fill or conform to very small features.

Typically, the chemistry, *i.e.*, the chemical formulations and conditions, used in conventional plating cells is designed to provide acceptable plating results when used in many different cell designs, on different plated parts and in numerous different applications. Cells which are not specifically designed to provide highly uniform current density (and the deposit thickness distribution) on specific plated parts require high conductivity solutions to be utilized to provide high 'throwing power' (also referred to as high Wagner number) so that good coverage is achieved on all surfaces of the plated object. Typically, a supporting electrolyte, such as an acid or a base, or occasionally a conducting salt, is added to the plating solution to provide the high ionic conductivity to the plating solution necessary to achieve high 'throwing power'. The supporting electrolyte does not participate in the electrode reactions, but is required in order to provide conformal coverage of the plated material over the surface of the object because it reduces the resistivity within the electrolyte, the higher resistivity that otherwise occurs being the cause of the non-uniformity in the current density. Even the addition of a small amount, *e.g.*, 0.2 Molar, of an acid or a base will typically increase the electrolyte conductivity quite significantly (*e.g.*, almost double the conductivity).

However, on objects such as semiconductor substrates that are resistive, *e.g.*, metal seeded wafers, high conductivity of the plating solution negatively affects the uniformity of the deposited film. This is commonly referred to as the terminal effect and is described

in a paper by Oscar Lanzi and Uziel Landau, "Terminal Effect at a Resistive Electrode Under Tafel Kinetics", J. Electrochem. Soc. Vol. 137, No. 4 pp. 1139-1143, April 1990, which is incorporated herein by reference. This effect is due to the fact that the current is fed from contacts along the circumference of the part and must distribute itself across a resistive substrate. If the electrolyte conductivity is high, such as in the case where excess supporting electrolyte is present, it will be preferential for the current to pass into the solution within a narrow region close to the contact points rather than distribute itself evenly across the resistive surface, i.e., it will follow the most conductive path from terminal to solution. As a result, the deposit will be thicker close to the contact points. Therefore, a uniform deposition profile over the surface area of a resistive substrate is difficult to achieve.

Another problem encountered with conventional plating solutions is that the deposition process on small features is controlled by mass transport (diffusion) of the reactants to the feature and by the kinetics of the electrolytic reaction instead of by the magnitude of the electric field as is common on large features. In other words, the replenishment rate at which plating ions are provided to the surface of the object can limit the plating rate, irrespective of voltage. Essentially, if the voltage dictates a plating rate that exceeds the local ion replenishment rate, the replenishment rate dictates the plating rate. Hence, highly conductive electrolyte solutions that provide conventional "throwing power" have little significance in obtaining good coverage and fill within very small features. In order to obtain good quality deposition, one must have high mass-transport rates and low depletion of the reactant concentration near or within the small features. However, in the presence of excess acid or base supporting electrolyte, (even a relatively small excess) the transport rates are diminished by approximately one half (or the concentration depletion is about doubled for the same current density). This will cause a reduction in the quality of the deposit and may lead to fill defects, particularly on small features.

It has been learned that diffusion is of significant importance in conformal plating and filling of small features. Diffusion of the metal ion to be plated is directly related to the concentration of the plated metal ion in the solution. A higher metal ion concentration results in a higher rate of diffusion of the metal into small features and in a higher metal ion concentration within the depletion layer (boundary layer) at the cathode surface, hence faster and better quality deposition may be achieved. In conventional plating applications,

the maximum concentration of the metal ion achievable is typically limited by the solubility of its salt. If the supporting electrolyte, e.g., acid, base, or salt, contain a co-ion which provides a limited solubility product with the plated metal ion, the addition of a supporting electrolyte will limit the maximum achievable concentration of the metal ion. This phenomenon is called the common ion effect. For example, in copper plating applications, when it is desired to keep the concentration of copper ions very high, the addition of sulfuric acid will actually diminish the maximum possible concentration of copper ions. The common ion effect essentially requires that in a concentrated copper sulfate electrolyte, as the sulfuric acid (H_2SO_4) concentration increases (which gives rise to H^+ cations and HSO_4^- and SO_4^{2-} anions), the concentration of the copper (II) cations decreases due to the greater concentration of the other anions. Consequently, conventional plating solutions, which typically contain excess sulfuric acid, are limited in their maximal copper concentration and, hence, their ability to fill small features at high rates and without defects is limited.

Therefore, there is a need for new formulations of metal plating solutions designed particularly to provide good quality plating of small features, e.g., micron scale and smaller features, on substrates and to provide uniform coating and defect-free fill of such small features.

SUMMARY OF THE INVENTION

The present invention provides plating solutions having novel blends of specific additives that enhance defect-free fill of small features. The plating solutions promote uniform metal deposition within the features and can provide highly reflective metal surfaces without polishing. The plating solutions typically contain little or no supporting electrolyte (*i.e.*, which include no acid, low acid, no base, or no conducting salts) and/or high metal ion concentration (*e.g.*, copper). The additives that enhance uniform deposition include a polyether ("carrier"), such as a polyalkylene glycol, wherein the concentration of the carrier ranges from about 0.1 ppm to about 2500 ppm of the plating solution. The additives further include an organic divalent sulfur compound ("accelerator"), wherein the concentration of the accelerator ranges from about 0.05 ppm to about 1000 ppm of the plating solution. The plating solution may further include halide ions at a concentration from about 5 ppm to about 400 ppm. The plating solutions may also contain additives which enhance the plated film quality and performance by serving, *inter alia*, as

brighteners, levelers, surfactants, grain refiners, and stress reducers. An organic nitrogen compound is preferably added to the compositions at a concentration from about 0.01 ppm to about 1000 ppm to improve the filling of vias on a resistive substrate. Most preferably a substituted thiadiazole such as 2-amino-5-methyl-1,3,4-thiadiazole or 2-amino-5-ethyl-1,3,4-thiadiazole is added to solutions that contain the polyether and the divalent sulfur compound..

DETAILED DESCRIPTION OF A PREFERRED EMBODIMENT

The present invention generally relates to electroplating solutions having low conductivity, particularly those solutions containing no supporting electrolyte or low concentration of supporting electrolyte, *i.e.*, essentially no acid or low acid concentration (preferably less than 0.1 molar acid solution, and where applicable, no or low base), essentially no conducting salts and high metal concentration to achieve good deposit uniformity across a resistive substrate and to provide good fill within very small features such as micron and sub-micron sized features and smaller. The invention provides plating solutions having high concentrations of metal ions and low concentrations of additives that provide uniform plating of the metal ions over the substrate and provide void free deposition within small features.

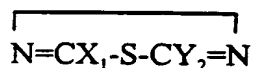
The additives to the plating solution preferably include blends of a polyether ("carrier"), an organic divalent sulfur compound ("accelerator"), and a nitrogen compound as described in more detail below.

The concentration of the carrier ranges from about 0.1 ppm to about 2500 ppm of the plating solution. Preferably the plating solution contains a polyalkylene glycol at a concentration of from about 0.5 ppm to about 2000 ppm. The polyalkylene glycols have a molecular weight from about 60 to about 100,000. A preferred polyalkylene glycol is UCON® 75-1400 polyalkylene glycol at a concentration from about 5 ppm to about 500 ppm.

The concentration of the "accelerator" ranges from about 0.05 ppm to about 1000 ppm of the plating solution. Preferably the plating solution comprises from about 0.1 ppm to about 60 ppm of an accelerator having the structure $R_1-(S)_n-R_2$, wherein R_1 and R_2 are the same or different organic groups, and n is the number of sulfur atoms between 1 and 6. Typically, R_1 and R_2 are the same or different alkyl groups terminated with an acid or a salt, such as a sulfonic acid or a sulfonate, a phosphoric acid or a phosphate, a nitric acid

or a nitrate, or a sulfuric acid or a sulfate. A preferred divalent sulfur compound is the disodium salt of 3,3-dithiobis-1-propanesulfonic acid.

Other additives are included, and may improve brightening and other properties of the resultant metal plated on substrates when used in electroplating solutions with no or low supporting electrolyte, *e.g.*, no or low acid. Filling of submicron features is enhanced by addition of soluble organic compounds containing nitrogen and sulfur bound to the same carbon atom by single or double bonds. Preferred additives are from about 0.1 ppm to about 1000 ppm of a nitrogen containing organic compound comprising a ring structure containing from 4 to 10 nitrogen, carbon, or sulfur atoms that form the ring, or from about 0.01 to about 500 ppm of a quaternary nitrogen compound or a nitrogen compound that forms a quaternary nitrogen compound in the plating solution. The preferred additives are from about 0.1 ppm to about 50 ppm of a substituted thiadiazole having the cyclic structure:



wherein X_1 and Y_2 can be the same or different groups, including amines, hydrogen, alkyl groups with 1 to 6 carbon atoms, ethyl-thio groups, hydroxyl or sulfonate groups. The preferred additives are 2-amino-5-methyl-1,3,4-thiadiazole, 2-amino-5-ethyl-1,3,4-thiadiazole, 2-amino-5-isopropyl-1,3,4-thiadiazole, and 2-amino-5-propyl-1,3,4-thiadiazole. The 5-methyl and 5-ethyl compounds have demonstrated improved filling of apertures on resistive substrates at reasonably high (40 to 60 mA/cm²) current density. The substituted thiadiazole is most preferably used at concentrations from about 0.5 ppm to about 5 ppm of the plating solution. The plating compositions alternatively can include a quaternary nitrogen compound selected from alkylated polyimines, phenazine dyes, triazoles, tetrazoles, or mixtures thereof

The plating solutions of the invention also preferably contain halide ions, such as chloride ions, bromide, fluoride, iodide, typically in amounts from 0 to about 0.2 g/L, preferably from about 5 ppm to about 400 ppm. However, this invention also contemplates the use of copper plating solutions without chloride or other halide ions.

The invention is described below in reference to plating of copper on substrates in the electronic industry. However, it is to be understood that the electroplating solutions, particularly those having low or complete absence of supporting electrolyte, can be used to

deposit other metals on resistive substrates and has application in any field where plating can be used to advantage.

In one embodiment of the invention, aqueous copper plating solutions are employed which are comprised of copper sulfate, preferably from about 200 to about 350 grams per liter (g/l) of copper sulfate pentahydrate in water (H_2O), and essentially no added sulfuric acid, or very low acid, less than 0.1 M. The copper concentration may be from about 0.1 to about 1.2 Molar, and is preferably greater than about 0.8 Molar. In addition to copper sulfate, the invention contemplates copper salts other than copper sulfate, such as copper fluoborate, copper gluconate, copper sulfamate, copper sulfonate, copper pyrophosphate, copper chloride, copper cyanide, copper citrate, and the like, all without (or with little) supporting electrolyte. Some of these copper salts offer higher solubility than copper sulfate, and therefore may be advantageous.

The conventional copper plating electrolyte includes a relatively high sulfuric acid concentration (from about 45 g of H_2SO_4 per L of H_2O (0.45M) to about 110 g/L (1.12M)) which is added to the solution to provide high conductivity to the electrolyte. The high conductivity is necessary to reduce the non-uniformity in the deposit thickness caused by the cell configuration and the differently shaped parts encountered in conventional electroplating cells. However, the present invention is directed primarily towards applications where the cell configuration has been specifically designed to provide a relatively uniform deposit thickness distribution on given parts. However, the substrate is resistive and imparts thickness non-uniformity to the deposited layer. Thus, among the causes of non-uniform plating, the resistive substrate effect may dominate and a highly conductive electrolyte, containing, e.g., high H_2SO_4 concentrations, is unnecessary. In fact, a highly conductive electrolyte (e.g., generated by a high sulfuric acid concentration) is detrimental to uniform plating because the resistive substrate effects are amplified by a highly conductive electrolyte. This is the consequence of the fact that the degree of uniformity of the current distribution, and the corresponding deposit thickness, is dependent on the ratio of the resistance to current flow within the electrolyte to the resistance of the substrate. The higher this ratio is, the lesser is the terminal effect and the more uniform is the deposit thickness distribution. Therefore, when uniformity is a primary concern, it is desirable to have a high resistance within the electrolyte. Since the electrolyte resistance is given by $l/\kappa\pi r^2$, it is advantageous to have as low a conductivity, κ , as possible, and also a large gap, l , between the anode and the cathode. Also, clearly, as

the substrate radius, r , becomes larger, such as when scaling up from 200 mm wafers to 300 mm wafers, the terminal effect will be much more severe (*e.g.*, by a factor of 2.25). By eliminating the acid, the conductivity of the copper plating electrolyte typically drops from about 0.5 S/cm ($0.5 \text{ ohm}^{-1}\text{cm}^{-1}$) to about 1/10 of this value, *i.e.*, to about 0.05 S/cm, making the electrolyte ten times more resistive.

Also, a lower supporting electrolyte concentration (*e.g.*, sulfuric acid concentration in copper plating) often permits the use of a higher metal ion (*e.g.*, copper sulfate) concentration due to elimination of the common ion effect as explained above. Furthermore, in systems where a soluble copper anode is used, a lower added acid concentration (or preferably no acid added at all) minimizes harmful corrosion and material stability problems. Additionally, a pure or relatively pure copper anode can be used in this arrangement. Because some copper dissolution typically occurs in an acidic environment in the presence of dissolved oxygen, copper anodes that are being used in conventional copper plating typically contain phosphorous. The phosphorous forms a film on the anode that protects it from excessive dissolution, but phosphorous traces will be found in the plating solution and also may be incorporated as a contaminant in the deposit. In applications using plating solutions with no acidic supporting electrolytes as described herein, the phosphorous content in the anode may, if needed, be reduced or eliminated. Also, for environmental considerations and ease of handling the solution, a non acidic or low acid electrolyte is preferred.

Another method for enhancing thickness uniformity includes applying a periodic current reversal. For this reversal process, it may be advantageous to have a more resistive solution (*i.e.*, no supporting electrolyte) since this serves to focus the dissolution current at the extended features that one would want to preferentially dissolve.

In some specific applications, it may be beneficial to introduce small amounts of acid, base or salts into the plating solution. Examples of such benefits may be some specific adsorption of ions that may improve specific deposits, complexation, pH adjustment, solubility enhancement or reduction and the like. Also, addition of a small amount of acid (*e.g.* sulfuric acid) will prevent the formation of copper oxides on the surfaces. The invention also contemplates the addition of such acids, bases or salts into the electrolyte in amounts up to about 0.4 M.

A plating solution having a high copper concentration (*i.e.*, $>0.4\text{M}$) is beneficial to overcome mass transport limitations that are encountered when plating small features. In

particular, because micron scale features with high aspect ratios typically allow only minimal or no electrolyte flow therein, the ionic transport relies solely on diffusion to deposit metal into these small features. A high copper concentration, preferably about 0.8 molar (M) or greater, in the electrolyte enhances the diffusion process and reduces or eliminates the mass transport limitations. The metal concentration required for the plating process depends on factors such as temperature and the acid concentration of the electrolyte.

The plating solutions of the present invention are typically used at current densities ranging from about 10 mA/cm² to about 80 mA/cm². Current densities as high as 100 mA/cm² and as low as 5 mA/cm² can also be employed under appropriate conditions. In plating conditions where a pulsed current or periodic reverse current is used, current densities in the range of about 5 mA/cm² to about 400 mA/cm² can be used periodically.

The operating temperatures of the plating solutions may range from about 0°C to about 95°C. Preferably, the solutions range in temperature from about 15°C to about 60°C.

The copper plating solutions of the invention preferably contain chloride ions, typically in amounts from about 30 ppm to about 120 ppm, most preferably from about 40 ppm to about 80 ppm. However, this invention also contemplates the use of copper plating solutions without chloride or other halide ions.

The copper plating solutions of the invention are suppressed by the polyalkylene glycol "carriers". An example of a preferred carrier that is commercially available is UCON Lubricant 75-H-1400 polyalkylene glycol available from Union Carbide Corp. of Danbury, CT. This carrier has a general formula of:



wherein x and y provide an approximate weight average molecular weight of 2500. The specific gravity is 1.095 at 20°C.

Copper plating solutions containing polyalkylene glycols are accelerated by organic divalent sulfur compounds having the structure R₁-(S)_n-R₂, wherein R₁ and R₂ are the same or different organic groups, and n is the number of sulfur atoms between 1 and 6. Preferably R₁ and R₂ are the same or different alkyl groups having from 1 to 8 carbon atoms, and are terminated with an acid or a salt, such as a sulfonic acid or a sulfonate. Commercially available organic divalent sulfur compounds include 'SPS' which is the disodium salt of 3,3-dithiobis-1-propanesulfonic acid, available from Raschig Corp. of

Richmond, VA. The commercial disodium salt comprises at least 80% of the SPS, and the remaining components include monosodium salts of 3-mercapto-1-propanesulfonic acid or 3-hydroxy-1-propanesulfonic acid. The commercial SPS may also contain the disodium salt of 3,3-thiobis-1-propanesulfonic acid.

In addition to the constituents described above, the copper plating solutions may contain various additives that are introduced typically in small (ppm range) amounts. The additives typically improve the thickness distribution (levelers), the reflectivity of the plated film (brighteners), its grain size (grain refiners), stress (stress reducers), adhesion and wetting of the part by the plating solution (wetting agents), and other process and film properties.

The additional additives typically constitute small amounts (ppm level) from one or more of the following groups of chemicals:

1. Organic nitrogen compounds and their corresponding salts and polyelectrolyte derivatives thereof.
2. Polar heterocycles

A preferred additive is 2-amino-5-methyl-1,3,4-thiadiazole, which is available from Aldrich, and is used at concentrations from 0.1 ppm to about 50 ppm of the plating solution, preferably from about 0.5 ppm to about 5 ppm. The additive enhances the surface brightness of the deposited metal and improves filling of sub-micron features with copper.

Further understanding of the present invention will be had with reference to the following examples which are set forth herein for purposes of illustration but not limitation.

Example I

An electroplating bath consisting of 210 g/L of copper sulfate pentahydrate was prepared. A flat tab of metallized wafer was then plated in this solution at an average current density of 40 mA/cm² and without agitation. The resulting deposit was dull and pink.

Example II

To the bath in example I was then added 50 mg/L of chloride ion in the form of HCl or CuCl₂. Another tab was then plated using the same conditions. The resulting deposit was shinier and showed slight grain refinement under microscopy.

Example III

An electroplating bath consisting of 210 g/L of copper sulfate pentahydrate and 50 mg/L of chloride ion was prepared. To the bath was added the following:

Compound	Approximate Amount (ppm)
UCON® 75-H-1400 (Polyalkylene glycol with an average molecular weight of 1400 commercially available from Union Carbide.)	100
SPS (organic divalent sulfur compound available from Raschig Corp.)	5
2-amino-5-methyl-1,3,4-thiadiazole (Available from Aldrich.)	0

A flat tab of metallized wafer was then plated in this solution at an average current density of 40 mA/cm² and without agitation. The resulting deposit was shinier than that in Comparison Example II. Microscopy revealed fine grains.

Example IV

An electroplating bath consisting of 210 g/L of copper sulfate pentahydrate and 50 mg/L of chloride ions was prepared. To the bath was added the following:

Compound	Approximate Amount (ppm)
UCON® 75-H-1400 (Polyalkylene glycol with an average molecular weight of 1400 commercially available from Union carbide)	100
SPS (organic divalent sulfur compound available from Raschig Corp.)	40
2-amino-5-methyl-1,3,4-thiadiazole (Available from Aldrich)	5

A flat tab of metallized wafer was then plated in this solution at an average current density of 40 mA/cm² and without agitation. The resulting deposit was mirror like. Microscopy revealed extremely fine grains.

The present invention is defined by the following claims, and is not generally limited to specific embodiments described in the specification or examples. Other embodiments will be apparent to persons skilled in the art after reading this application.

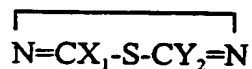
CLAIMS:

1. A method for electrolytic plating a metal comprising copper on an electrically resistive substrate, comprising:
disposing an electrically resistive substrate having submicron features and an anode in a plating solution, comprising:
metal ions at a molar concentration from about 0.1 to about 1.2; and
a polyether at a concentration from about 0.1 ppm to about 2500 ppm of the plating solution; and
electrodepositing the metal onto the electronically resistive substrate from the metal ions in the solution.
2. The method of claim 1, wherein the plating solution further comprises halide ions at a concentration from about 5 ppm to about 400 ppm.
3. The method of claim 1, wherein the plating solution further comprises chloride ions at a concentration from about 30 ppm to about 120 ppm.
4. The method of claim 1, wherein the plating solution further comprises a divalent sulfur compound at a concentration from about 0.05 ppm to about 1000 ppm.
5. The method of claim 2, wherein the plating solution further comprises a divalent sulfur compound at a concentration from about 0.1 ppm to about 60 ppm..
6. The method of claim 1, wherein the plating solution further comprises a soluble organic compound containing nitrogen and sulfur bound to the same carbon atom by single or double bonds.
7. The method of claim 1, wherein the plating solution further comprises a quaternary nitrogen compound selected from a group consisting of alkylated polyimines, phenazine dyes, triazoles, tetrazoles, and mixtures thereof.

8. The method of claim 6, wherein the copper ions are provided by a copper salt selected from copper sulfate, copper fluoborate, copper gluconate, copper sulfamate, copper sulfonate, copper pyrophosphate, copper chloride, copper cyanide, copper citrate, or mixtures thereof.
9. The method of claim 7, wherein the copper ion concentration is greater than about 0.8 molar.
10. The method of claim 1, wherein the concentration of the acid or the supporting electrolyte is less than 0.1 M.
11. The method of claim 1, wherein the polyether is UCON[®] 75-H-1400 polyalkylene glycol at a concentration of from about 5 ppm to about 500 ppm.
12. The method of claim 1, wherein the organic divalent sulfur compound is a disodium salt of 3,3-dithiobis-1-propanesulfonic acid at a concentration of from about 0.05 ppm to about 1000 ppm.
13. The method of claim 1, further comprising from about 0.1 to about 50 ppm of 2-amino-5-methyl-1,3,4-thiadiazole, 2-amino-5-ethyl-1,3,4-thiadiazole, 2-amino-5-isopropyl-1,3,4-thiadiazole, and 2-amino-5-propyl-1,3,4-thiadiazole.
14. A solution for electroplating copper onto a substrate, comprising:
 - water;
 - copper ions at a molar concentration from 0.1 to 1.2, wherein the copper ions are obtained from copper sulfate, copper fluoborate, copper gluconate, copper sulfamate, copper pyrophosphate, copper chloride, copper cyanide, copper citrate, or mixtures thereof;
 - a polyalkylene glycol at a concentration from about 0.1 ppm to about 2500 ppm of plating solution;
 - a divalent sulfur compound at a concentration from about 0.05 ppm to about 1000 ppm of plating solution, the sulfur compound having the structure $R_1-(S)_n-R_2$, wherein R_1

and R_2 are the same or different organic groups, and n is the number of sulfur atoms between 1 and 6; and

a substituted thiodiazole at a concentration of from about 0.1 ppm to about 50 ppm of plating solution, the substituted thiodiazole having the cyclic structure:



wherein X_1 and Y_2 can be the same or different groups.

15. The solution of claim 14, wherein the plating solution further comprises chloride ions at a concentration from about 30 ppm to about 120 ppm.
16. The solution of claim 14, wherein the polyalkylene glycol is UCON® 75-H-1400 polyalkylene glycol at a concentration of from about 5 ppm to about 500 ppm.
17. The solution of claim 14, wherein the a divalent sulfur compound is the disodium salt of 3,3-dithiobis-1-propanesulfonic acid at a concentration of from about 0.1 ppm to about 60 ppm..
18. The solution of claim 14, wherein the concentration of the acid or supporting electrolyte is essentially less than about 0.1 M.
19. The solution of claim 14, wherein the plating solution comprises from 2 to about 5 ppm of 2-amino-5-methyl-1,3,4-thiadiazole, 2-amino-5-ethyl-1,3,4-thiadiazole, 2-amino-5-isopropyl-1,3,4-thiadiazole, or 2-amino-5-propyl-1,3,4-thiadiazole.
20. The solution of claim 19, wherein the plating solution comprises from about 2 ppm to about 5 ppm of 2-amino-5-methyl-1,3,4-thiadiazole or 2-amino-5-ethyl-1,3,4-thiadiazole.

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property Organization
International Bureau



(43) International Publication Date
20 July 2000 (20.07.2000)

PCT

(10) International Publication Number
WO 00/41518 A3

- (51) International Patent Classification⁷: **C25D 3/38**
- (21) International Application Number: **PCT/US00/00155**
- (22) International Filing Date: **5 January 2000 (05.01.2000)**
- (25) Filing Language: **English**
- (26) Publication Language: **English**
- (30) Priority Data:
09/227,957 11 January 1999 (11.01.1999) US
09/263,653 5 March 1999 (05.03.1999) US
- (71) Applicant: **APPLIED MATERIALS, INC.** [US/US];
3050 Bowers Avenue, Santa Clara, CA 95054 (US).
- (72) Inventors: **LANDAU, Uziel**; 13909 Larchmere Boulevard, Cleveland, OH 44120 (US). **D'URSO, John, J.**; 2307 South Glenwood Avenue, Niles, OH 44446 (US).
- (74) Agents: **PATTERSON, B., Todd et al.**; Thomason, Moser & Patterson, L.L.P., Suite 1500, 3040 Post Oak Boulevard, Houston, TX 77056 (US).
- (81) Designated States (*national*): CN, JP, KR.
- (84) Designated States (*regional*): European patent (AT, BE, CH, CY, DE, DK, ES, FI, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).
- Published:
— With international search report.
— Before the expiration of the time limit for amending the claims and to be republished in the event of receipt of amendments.
- (88) Date of publication of the international search report:
30 November 2000
- For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.



WO 00/41518 A3

(54) Title: **ELECTRODEPOSITION CHEMISTRY FOR FILLING OF APERTURES WITH REFLECTIVE METAL**

(57) Abstract: The present invention provides plating solutions, particularly copper plating solutions, designed to provide uniform coatings on substrates and to provide substantially defect free filling of small features formed on substrates with none or low supporting electrolyte, *i.e.*, which include no acid, low acid, no base, or no conducting salts, and/or high metal ion, *e.g.*, copper, concentration. Defect free filling of features is enhanced by a plating solution containing blends of polyethers ("carrier") and organic divalent sulfur compounds ("accelerator"), wherein the concentration of the carrier ranges from about 0.1 ppm to about 2500 ppm of the plating solution, and the concentration of the accelerator ranges from about 0.05 ppm to about 1000 ppm of the plating solution. The plating solution is further improved by adding an organic nitrogen compound at a concentration from about 0.01 ppm to about 1000 ppm to improve the filling of vias on a resistive substrate. The organic nitrogen is preferably a substituted thiadiazole, which is used at concentrations from 0.1 ppm to about 50 ppm of the plating solution, or a quaternary nitrogen compound, which is used at concentrations from about 0.01 ppm to about 500 ppm.

INTERNATIONAL SEARCH REPORT

International Application No

PCT/US 00/00155

A. CLASSIFICATION OF SUBJECT MATTER

IPC 7 C25D3/38

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 C25D

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, CHEM ABS Data, WPI Data, PAJ, INSPEC

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X,P	EP 0 952 242 A (APPLIED MATERIALS INC) 27 October 1999 (1999-10-27) the whole document	1-11,15, 16,18
X	EP 0 163 131 A (LEARONAL INC) 4 December 1985 (1985-12-04) the whole document	1-4,6,8, 12,15,17
X	JAMES J. KELLY CS: "Copper Deposition in the Presence of Polyethylene Glycol. I. Quartz Crystal" J. ELECTROCHEM. SOC., vol. 145, no. 10, 30 October 1998 (1998-10-30), pages 3472-3476, XP002148319 the whole document	1-3,8,15

-/--



Further documents are listed in the continuation of box C.



Patent family members are listed in annex.

* Special categories of cited documents :

- "A" document defining the general state of the art which is not considered to be of particular relevance
- "E" earlier document but published on or after the international filing date
- "L" document which may throw doubts on priority claim(s) or which is cited to establish the publication date of another citation or other special reason (as specified)
- "O" document referring to an oral disclosure, use, exhibition or other means
- "P" document published prior to the international filing date but later than the priority date claimed

- "T" later document published after the international filing date or priority date and not in conflict with the application but cited to understand the principle or theory underlying the invention
- "X" document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- "Y" document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
- "&" document member of the same patent family

Date of the actual completion of the international search

28 September 2000

Date of mailing of the international search report

11/10/2000

Name and mailing address of the ISA

European Patent Office, P.B. 5818 Patentaan 2
NL - 2280 HV Rijswijk
Tel. (+31-70) 340-2040, Tx. 31 651 epo nl,
Fax: (+31-70) 340-3016

Authorized officer

Van Leeuwen, R

INTERNATIONAL SEARCH REPORT

International Application No.

PCT/US 00/00155

C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	US 3 161 575 A (WELLS) 15 December 1964 (1964-12-15) claims 1,2 ---	6,7,13, 19,20
A	PATENT ABSTRACTS OF JAPAN vol. 009, no. 188 (C-295), 3 August 1985 (1985-08-03) & JP 60 056086 A (HODOGAYA KAGAKU KOGYO KK), 1 April 1985 (1985-04-01) abstract ---	1,4,5,7, 8,12,14, 17
A	US 5 328 589 A (MARTIN SYLVIA) 12 July 1994 (1994-07-12) column 4, line 16-63; examples 1-4 -----	1-5,8, 11,12, 14-17

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No

PCT/US 00/00155

Patent document cited in search report		Publication date	Patent family member(s)	Publication date
EP 0952242	A	27-10-1999	US 6113771 A EP 0991795 A JP 11310896 A WO 9954527 A	05-09-2000 12-04-2000 09-11-1999 28-10-1999
EP 0163131	A	04-12-1985	US 4490220 A AT 45193 T DE 3572013 D JP 1512481 C JP 61019791 A JP 63057510 B	25-12-1984 15-08-1989 07-09-1989 09-08-1989 28-01-1986 11-11-1988
US 3161575	A	15-12-1964	DE 1225938 B FR 1295775 A GB 939997 A NL 123240 C NL 267368 A	07-11-1962
JP 60056086	A	01-04-1985	NONE	
US 5328589	A	12-07-1994	CA 2110214 A DE 4343946 A ES 2088356 A FR 2699556 A GB 2273941 A, B HK 28197 A IT 1261377 B JP 6228785 A	24-06-1994 30-06-1994 01-08-1996 24-06-1994 06-07-1994 21-03-1997 20-05-1996 16-08-1994